

Is Now Part of



ON Semiconductor®

To learn more about ON Semiconductor, please visit our website at <u>www.onsemi.com</u>

ON Semiconductor and the ON Semiconductor logo are trademarks of Semiconductor Components Industries, LLC dba ON Semiconductor or its subsidiaries in the United States and/or other countries. ON Semiconductor owns the rights to a number of patents, trademarks, copyrights, trade secrets, and other intellectual property. A listing of ON Semiconductor's product/patent coverage may be accessed at www.onsemi.com/site/pdf/Patent-Marking.pdf. ON Semiconductor reserves the right to make changes without further notice to any products herein. ON Semiconductor makes no warranty, representation or guarantee regarding the suitability of its products for any particular purpose, nor does ON Semiconductor assume any liability arising out of the application or use of any product or circuit, and specifically disclaims any and all liability, including without limitation special, consequential or incidental damages. Buyer is responsible for its products and applications using ON Semiconductor dates sheds, regardless of any support or applications information provided by ON Semiconductor. "Typical" parameters which may be provided in ON Semiconductor dates sheds and/or specifications can and do vary in different applications and actual performance may vary over time. All operating parameters, including "Typicals" must be validated for each customer application by customer's technical experts. ON Semiconductor does not convey any license under its patent rights of others. ON Semiconductor products are not designed, intended, or authorized for use on similar classification in a foreign jurisdiction or any devices intended for implantation in the human body. Should Buyer purchase or use ON Semiconductor and its officers, employees, subsidiaries, affliates, and distributors harmless against all claims, costs, damages, and expenses, and reasonable attorney fees arising out or i, directly or indirectly, any lay bed ON Semiconductor and its officers, employees, ween if such claim alleges that ON Semiconductor was negligent regarding the d



N-Channel Shielded Gate PowerTrench[®] MOSFET 100 V, 16 A, 24 m Ω

Features

- Shielded Gate MOSFET Technology
- Max $r_{DS(on)} = 24 \text{ m}\Omega$ at $V_{GS} = 10 \text{ V}$, $I_D = 7 \text{ A}$
- Max $r_{DS(on)}$ = 39 m Ω at V_{GS} = 6 V, I_D = 5.5 A
- Advanced Package and Silicon combination for low r_{DS(on)} and high efficiency
- MSL1 robust package design
- 100% UIL tested
- RoHS Compliant

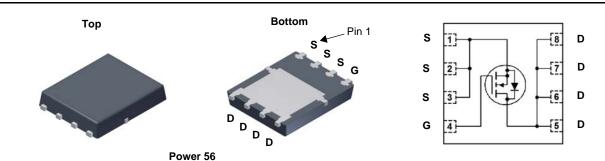


General Description

This N-Channel MOSFET is produced using Fairchild Semiconductor's advanced PowerTrench[®] process that incorporates Shielded Gate technology. This process has been optimized for the on-state resistance and yet maintain superior switching performance.

Application

DC-DC Conversion



MOSFET Maximum Ratings T_A = 25 °C unless otherwise noted

Symbol	Parameter			Ratings	Units	
V _{DS}	Drain to Source Voltage			100	V	
V _{GS}	Gate to Source Voltage			±20	V	
	Drain Current -Continuous	T _C = 25 °C		16		
I _D	-Continuous	T _A = 25 °C	(Note 1a)	7	А	
	-Pulsed	-Pulsed				
E _{AS}	Single Pulse Avalanche Energy		(Note 3)	96	mJ	
P _D	Power Dissipation	T _C = 25 °C		73	W	
	Power Dissipation	T _A = 25 °C	(Note 1a)	2.5		
T _J , T _{STG}	Operating and Storage Junction Temperature Range			-55 to +150	°C	

Thermal Characteristics

$R_{ ext{ heta}JC}$	Thermal Resistance, Junction to Case	1.7	°C/W
$R_{ ext{ heta}JA}$	Thermal Resistance, Junction to Ambient (Note 1	a) 50	C/VV

Package Marking and Ordering Information

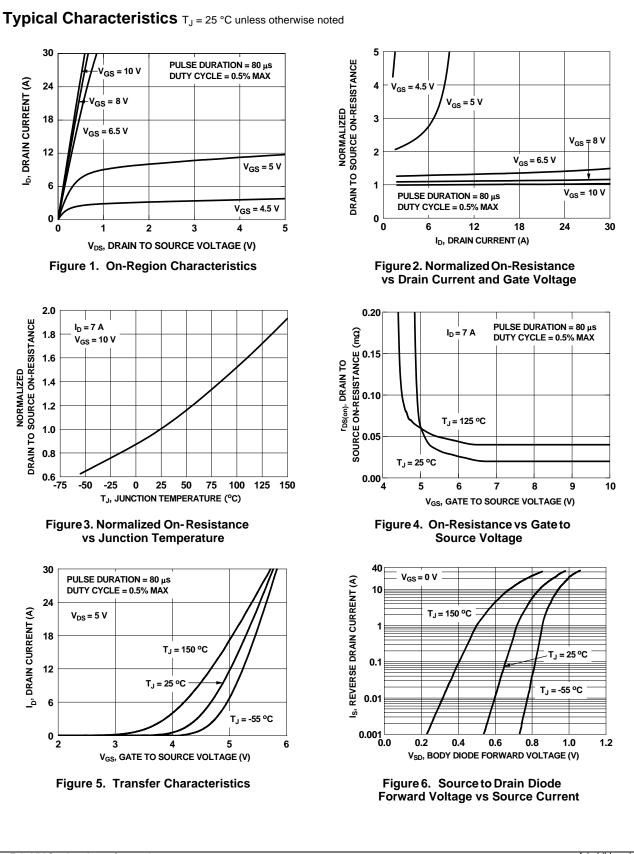
Device Marking Device		Package	Reel Size	Tape Width	Quantity
FDMS86104	IS86104 FDMS86104 Power 56		13 "	12 mm	3000 units

October 2014

Parameter	Test Conditions	Min	Тур	Max	Units
cteristics					
Drain to Source Breakdown Voltage	I _D = 250 μA, V _{GS} = 0 V	100			V
Breakdown Voltage Temperature			66		mV/°C
Coefficient	-		00		IIIV/ C
Zero Gate Voltage Drain Current				1	μA
Gate to Source Leakage Current	$V_{GS} = \pm 20 \text{ V}, V_{DS} = 0 \text{ V}$			±100	nA
cteristics					
Gate to Source Threshold Voltage	$V_{GS} = V_{DS}, I_{D} = 250 \ \mu A$	2	2.9	4	V
Gate to Source Threshold Voltage			10		
Temperature Coefficient	-		-10		mV/°C
	$V_{GS} = 10 \text{ V}, \text{ I}_{D} = 7 \text{ A}$		20	24	
Static Drain to Source On Resistance	$V_{GS} = 6 \text{ V}, \text{ I}_{D} = 5.5 \text{ A}$		27	39	mΩ
			33	40	
Forward Transconductance	$V_{DS} = 10 \text{ V}, I_{D} = 7 \text{ A}$		18		S
Characteristics					
			694	923	pF
	V _{DS} = 50 V, V _{GS} = 0 V, f = 1 MHz		178	237	pF
			8	13	pF
Gate Resistance			0.5		Ω
Characteristics					
Turn-On Delay Time			8	16	ns
Rise Time	$V_{DD} = 50 \text{ V}, \text{ I}_{D} = 7 \text{ A},$		3.5	10	ns
Turn-Off Delay Time	V_{GS} = 10 V, R_{GEN} = 6 Ω		14.3	26	ns
Fall Time			3.2	10	ns
Total Gate Charge	$V_{GS} = 0 V \text{ to } 10 V$		11.7	16	nC
Total Gate Charge	$V_{GS} = 0 V \text{ to } 5 V V_{DD} = 50 V,$		6.7	9	
Gate to Source Charge	I _D = 7 A		3.2		nC
Gate to Drain "Miller" Charge			3		nC
urce Diode Characteristics					
	$V_{GS} = 0 V, I_S = 2 A$ (Note 2)		0.7	1.2	
Source to Drain Diode Forward Voltage					V
Course to Brain Blode Torward Vollage			0.8	1.3	v
Reverse Recovery Time			0.8 44	1.3 70	ns
	Breakdown Voltage Temperature Coefficient Zero Gate Voltage Drain Current Gate to Source Leakage Current cteristics Gate to Source Threshold Voltage Gate to Source Threshold Voltage Gate to Source Threshold Voltage Temperature Coefficient Static Drain to Source On Resistance Forward Transconductance Characteristics Input Capacitance Output Capacitance Gate Resistance Characteristics Turn-On Delay Time Rise Time Turn-Off Delay Time Fall Time Total Gate Charge Gate to Source Charge	Breakdown Voltage Temperature CoefficientIJ 300 II $= 250 \ \mu$ A, referenced to $25 \ ^{\circ}$ CZero Gate Voltage Drain CurrentVV $S = 80 \ V, V_{GS} = 0 \ V$ Gate to Source Leakage CurrentVV $S = 250 \ \mu$ AGate to Source Threshold VoltageI $V_{GS} = \pm 20 \ V, V_{DS} = 0 \ V$ CteristicsII $= 250 \ \mu$ A, referenced to $25 \ ^{\circ}$ CGate to Source Threshold VoltageII $= 250 \ \mu$ A, referenced to $25 \ ^{\circ}$ CTemperature CoefficientII $= 250 \ \mu$ A, referenced to $25 \ ^{\circ}$ CStatic Drain to Source On ResistanceVV $I_D = 7 \ A$ Static Drain to Source On ResistanceVV $I_D = 7 \ A$ CharacteristicsInput CapacitanceV $V_{DS} = 10 \ V, I_D = 7 \ A$ Input CapacitanceVV $I_D = 70 \ V, V_{GS} = 0 \ V, I_D = 7 \ A$ Output CapacitanceV $I_D = 50 \ V, I_D = 7 \ A, V_{GS} = 10 \ V, I_D = 7 \ A, V_{GS} = 10 \ V, I_D = 7 \ A, V_{GS} = 10 \ V, I_D = 7 \ A, V_{GS} = 10 \ V, I_D = 7 \ A, V_{GS} = 10 \ V, I_D = 7 \ A, V_{GS} = 10 \ V, I_D = 7 \ A, V_{GS} = 10 \ V, I_D = 50 \ V, I_D = 7 \ A, V_{GS} = 0 \ V to 5 \ V, I_D = 7 \ A, V_{GS} = 0 \ V to 5 \ V, I_D = 7 \ A, V_{GS} = 0 \ V to 5 \ V, I_D = 7 \ A, V_{GS} = 0 \ V to 5 \ V, I_D = 7 \ A, V_{GS} = 0 \ V to 5 \ V, I_D = 7 \ A, V_{DD} = 50 \ V, I_D = 7 \ A, V_{DD} = 50 \ V, I_D = 7 \ A, V_{DD} = 50 \ V, I_D = 7 \ A, V_{DD} = 50 \ V, I_D = 7 \ A, V_{DD} = 50 \ V, I_D = 7 \ A, V_{DD} = 50 \ V, I_D = 7 \ A, V_{DD} = 50 \ V, I_D = 7 \ A, V_{DD} = 7 \ A, V_{DD} = 7 \ A, V_{DD} = 7 \ A,$	Breakdown Voltage Temperature CoefficientI D 250μ A, referenced to $25 ^{\circ}$ CZero Gate Voltage Drain CurrentV D S = 80 V, V GS = 0 VVGate to Source Leakage CurrentV V S = $\pm 20 ^{\circ}$ V, V D S = 0 V2CteristicsGate to Source Threshold Voltage 	$\begin{array}{c c c c c c c c c c c c c c c c c c c $	$\begin{array}{c c c c c c c c c c c c c c c c c c c $

3. Starting T_J = 25 °C, L = 3 mH, I_{AS} = 8 A, V_DD = 100 V, V_{GS} = 10 V

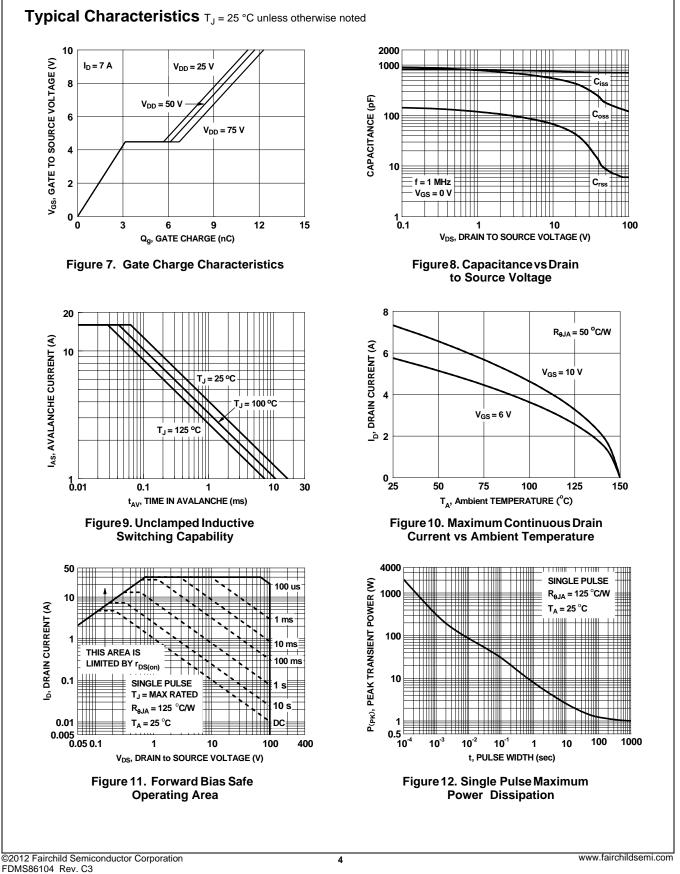
www.fairchildsemi.com



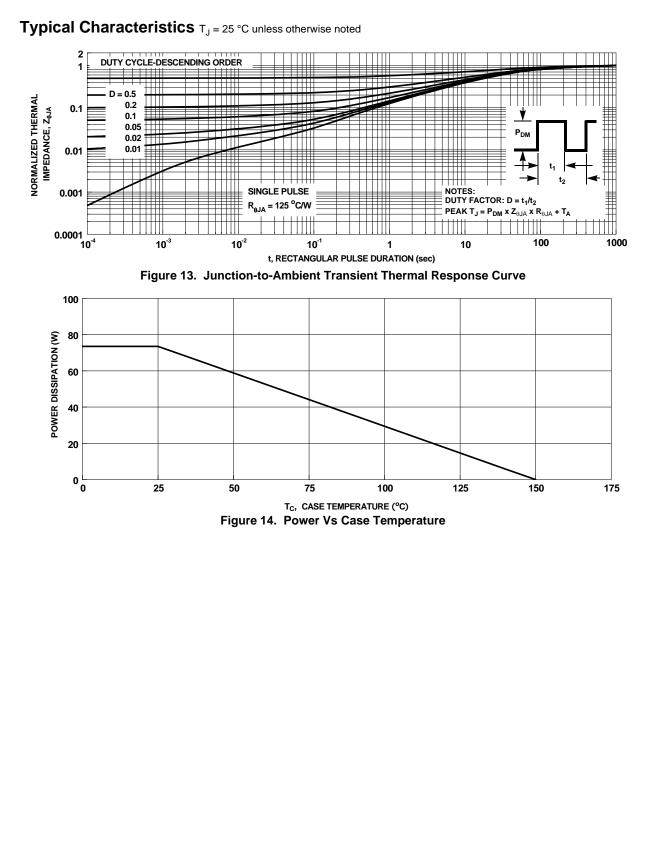
©2012 Fairchild Semiconductor Corporation FDMS86104 Rev. C3

I_D, DRAIN CURRENT (A)

www.fairchildsemi.com



FDMS86104 N-Channel Shielded Gate PowerTrench[®] MOSFET







* Trademarks of System General Corporation, used under license by Fairchild Semiconductor.

DISCLAIMER

FAIRCHILD SEMICONDUCTOR RESERVES THE RIGHT TO MAKE CHANGES WITHOUT FURTHER NOTICE TO ANY PRODUCTS HEREIN TO IMPROVE RELIABILITY, FUNCTION, OR DESIGN. TO OBTAIN THE LATEST, MOST UP-TO-DATE DATASHEET AND PRODUCT INFORMATION, VISIT OUR WEBSITE AT <u>HTTP://WWW.FAIRCHILDSEMI.COM</u>, FAIRCHILD DOES NOT ASSUME ANY LIABILITY ARISING OUT OF THE APPLICATION OR USE OF ANY PRODUCT OR CIRCUIT DESCRIBED HEREIN; NEITHER DOES IT CONVEY ANY LICENSE UNDER ITS PATENT RIGHTS, NOR THE RIGHTS OF OTHERS. THESE SPECIFICATIONS DO NOT EXPAND THE TERMS OF FAIRCHILD'S WORLDWIDE TERMS AND CONDITIONS, SPECIFICALLY THE WARRANTY THEREIN, WHICH COVERS THESE PRODUCTS.

AUTHORIZED USE

Unless otherwise specified in this data sheet, this product is a standard commercial product and is not intended for use in applications that require extraordinary levels of quality and reliability. This product may not be used in the following applications, unless specifically approved in writing by a Fairchild officer: (1) automotive or other transportation, (2) military/aerospace, (3) any safety critical application – including life critical medical equipment – where the failure of the Fairchild product reasonably would be expected to result in personal injury, death or property damage. Customer's use of this product is subject to agreement of this Authorized Use policy. In the event of an unauthorized use of Fairchild's product, Fairchild accepts no liability in the event of product failure. In other respects, this product shall be subject to Fairchild's Worldwide Terms and Conditions of Sale, unless a separate agreement has been signed by both Parties.

ANTI-COUNTERFEITING POLICY

Fairchild Semiconductor Corporation's Anti-Counterfeiting Policy. Fairchild's Anti-Counterfeiting Policy is also stated on our external website, www.fairchildsemi.com, under Terms of Use

Counterfeiting of semiconductor parts is a growing problem in the industry. All manufacturers of semiconductor products are experiencing counterfeiting of their parts. Customers who inadvertently purchase counterfeit parts experience many problems such as loss of brand reputation, substandard performance, failed applications, and increased cost of production and manufacturing delays. Fairchild is taking strong measures to protect ourselves and our customers from the proliferation of counterfeit parts. Fairchild strongly encourages customers to purchase Fairchild parts either directly from Fairchild or from Authorized Fairchild Distributors who are listed by country on our web page cited above. Products customers buy either from Fairchild directly or from Authorized Fairchild Distributors are genuine parts, have full traceability, meet Fairchild's quality standards for handling and storage and provide access to Fairchild's full range of up-to-date technical and product information. Fairchild and our Authorized Distributors will stand behind all warranties and will appropriately address any warranty issues that may arise. Fairchild will not provide any warranty coverage or other assistance for parts bought from Unauthorized Sources. Fairchild is committed to combat this global problem and encourage our customers to do their part in stopping this practice by buying direct or from authorized distributors.

PRODUCT STATUS DEFINITIONS

Definition of Terms				
Datasheet Identification	Product Status	Definition		
Advance Information	Formative / In Design	Datasheet contains the design specifications for product development. Specifications may change in any manner without notice.		
Preliminary	First Production	Datasheet contains preliminary data; supplementary data will be published at a later date. Fairchild Semiconductor reserves the right to make changes at any time without notice to improve design.		
No Identification Needed	Full Production	Datasheet contains final specifications. Fairchild Semiconductor reserves the right to make changes at any time without notice to improve the design.		
Obsolete	Not In Production	Datasheet contains specifications on a product that is discontinued by Fairchild Semiconductor. The datasheet is for reference information only.		

Rev. 177